

IECEE

CB-SCHEME

OD-CB2018-Ed.7.8

OPERATIONAL & RULING DOCUMENTS

**IECEE GROUPS: WORKING GROUPS
AND TASK FORCES**

OD-CB2018-Ed.7.8

IEC - IECEE 2010 - Copyright

2010-01-26

all rights reserved

Except for IECEE members and mandated persons, no part of this publication may be reproduced or utilized in any form or by any means, electronic or mechanical, including photocopying and microfilm, without permission writing from the publisher

IECEE Secretariat, 3, rue de Varembé, Geneva, Switzerland, Telefax : +41 22 919 0300, e-mail : pro@iec.ch



**IEC System for Conformity Testing and
Certification of Electrotechnical Equipment
and Components
CB Scheme**

INDEX

INDEX..... 2

BOA (Board of Appeals) 3

PAC (previously AAG) 4

CAG (Chairman's Advisory Group)..... 5

POLICY & STRATEGY FORUM..... 6

CMC - WORKING GROUPS 7

FCS – TASK FORCES and WORKING GROUPS 15

CTL WORKING GROUPS and TASK FORCES 16

IEC CAB TECHNICAL PANEL 25

JWG – JOINT WORKING GROUP..... 26



**IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components
CB Scheme**

BOA (Board of Appeals)

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
BOA (Board of Appeals)	CMC	<p>Don MADER (UL), Chairman <u>Members:</u> Joe GRYN (ULC) Paul MOLISKI (ITS USA as of 2009-01-01) Trond SOLLIE (NEMKO) Bo YUMIN (CNCA) Yoji ONO (JQA) <u>Deputies:</u> Gerhard DREGER (VDE) Paul TAN (PSB Corp.) Jukka VUORINEN (SGS Fimko) Ted GAERTNER (KEMA)</p>	<p>a) to recommend a solution to any dispute referred to it with regard to the application of these basic rules, and b) to recommend actions to be taken against NCBs and CBTLs on complaints received regarding potential infringements to the Rules that could compromise the credibility of the IECEE Schemes. c) to report to the CMC, for appropriate action, any observations relating to the technical content of the standards accepted for use in the IECEE and their applications, that has become evident when investigating a dispute</p>	

[Back to index](#)



**IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components
CB Scheme**

PAC (previously AAG)

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
PAC	CMC	P.de RUVO (IECEE Secretary) - Chair J. XIE (CNCA – Vice Chairman) Jing BIAN (CQC) Gerhard DREGER (VDE) Joe GRYN (ULC) Alberto PEDERNESCHI (IMQ) Masahiro SATO (JET) Trond SOLLIE (NEMKO) Wolfgang KREINBERG (TUV PS) Ted GAERTNER (Kema) Jung Sup KIM (KTL) Observer as member of PAAG: Craig DIACK-EVANS (ASTA)	<ul style="list-style-type: none"> •To monitor the Peer Assessment Program •To determine common understanding of ISO/IEC Guide 65 and ISO/IEC 17025 •To clarify matters pertaining to Certification issues •To evaluate the Assessment Reports of candidate NCBs and CBTLs and make recommendations to the CMC •To support and contribute as lecturers at the IECCE Lead and Technical Assessor training courses 	
PAC SG1 (previously WG 11) "PEER ASSESSMENT DOCUMENTS"		P. de RUVO (Convenor) Don MADER (UL INC) Trond SOLLIE (NEMKO) Wolfgang KREINBERG (TUV PS) Alberto PEDERNESCHI (IMQ) Joe GRYN (ULC)	Maintenance of NCB and CBTL assessments reports	

[Back to index](#)



**IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components
CB Scheme**

CAG (Chairman's Advisory Group)

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
CAG (Chairman's Advisory Group)	CMC	Gosta FREDRIKSSON (IECEE Chairman) Pierre de RUVO (IECEE Executive Secretary) Jun XIE (IECEE Vice-Chairman) Fritz BEGLINGER (Treasurer IECEE) Don MADER (UL) Trond SOLLIE (NEMKO) Kurt HEINZ (TÜV Rh JAPAN) Kiyoto MITSUI (JISC) Gerhard DREGER (VDE) Joe GRYN (ULC) Wolfgang KREINBERG (TUV PS) Ex-Officio: Aharon AMIT (General Secretary IEC)	To advise the IECEE Officers on issues that are decided by the Chairman and tabled at each meeting.	February 25 th , 2004

[Back to index](#)



IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components CB Scheme

POLICY & STRATEGY FORUM

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
Policy & Strategy Forum	CMC	<p>G. Fredriksson (Convenir) P. de RUVO (Secretary)</p> <p>Senior Conformity Assessment Delegate Members Joe Gryn (ULC) Du Chunjing (CNCA) Alternate: Bian Jing (CQC) Gerhard Dreger (VDE) Jukka Vuorinen (SGS Fimko Ltd) Michel Brenon (LCIE) Doron Tamir (SII) Giancarlo Zappa (IMQ) Toshiyuki Nawata(JISC) Mike Lawson (ASTABEAB) Don Mader (UL Inc) Alternate: Dave Surber (TUV Rheinland) Gitte SCHJOTZ (UL Demko) Franklin Willemstein (KEMA) Fredrik Wennersten (Intertek SEMKO)</p> <p>Senior Industry Delegate Members: Bill Bryans (BryBrook Consulting) YU Zida (China Haier Group Corporation) Uwe Kampet (BSH) Alternate: Jörg Hartge (ZVEI) Jari Yli-Juuti (ABB Finland) Jean-Pierre Isnard (FIEEC) Giovanni Cassinelli (Bticino S.p.A) Alternate Matteo Gavazzeni (GEWISS S.p.A) Toshiyuki Kajiya (Panasonic) Bob Taylor (Coutant Lambda Ltd.) Richard Pescatore (USNC/IECEE) Alternate: John Mahanna (IBM) Tim Duffy (Rockwell Automation) Wim Honig (Philips) Stefan Kjellnäs (ABB)</p>	<p>To identify market needs and propose IECEE market solutions to meet those needs and to maintain high quality third party conformity assessment principles.</p> <p>To propose mechanisms for ensuring that the IECEE Conformity Assessment solutions are recognized as the basis for certification and acceptance in regulated markets world wide in a timely way.</p> <p>To develop a framework or road map for the development of conformity assessment solutions within the IECEE scheme including such elements as:</p> <p>a) Type Test Certification b) Access to the marks of other Certification Bodies c) Full Certification Scheme. d) IECEE Conformity Assessment solutions that facilitate market access and relevance, including SDoC.</p>	2008-06-09



IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components CB Scheme

CMC - WORKING GROUPS

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
CMC-WG 2 "Business Development"	CMC	Wolfgang KREINBERG (TUV PS-Convenor) Toshiyuki NAWATA (JISC) Kenji FUKASAWA (JQA) Kurt HEINZ (TUV RH JP) Uwe KAMPET (GERMAN-NC/IECEE) Representative ASIA-PACIFIC Trond SOLLIE (NEMKO) Jukka VUORINEN (SGS Fimko) Yaacov WACHTEL (SII) Steven MARGIS (UL) Fulvio GIORGI (IMQ) Ron Collis (Rockwell Automation) Nick Maalouf (QPS)	To explore further the market needs focusing around the electrotechnical sector (i.e. EMC, etc.) as well as other fields of interest for the industry. To analyze and survey any possible business development services that could be of interest for the IECEE	To be determined
CMC-WG 3 "MTL"	CMC	Michel BRENON (LCIE Secretary-Convenor) Joe GRYN (ULC) Fulvio GIORGI (IMQ) Randolph KELLER (TÜV Rh Jap) Tuneyuki SATO (JET) Wolfgang KREINBERG (TÜV P.S.) Robin TIZZARD (BSI) Richard PESCATORE (USNC/IECEE) Jim CONROY (ITS Boxborough) Alternate: Craig DAVENPORT (ITS) Donald MADER (UL INC) Ilan CARMIT (SII)	To analyse and develop procedures related to the Manufactory Testing Laboratories programme.	September 19th, 2002, Geneva, IECEE Secretariat, Salle Bois
CMC-WG 4 "Components Acceptance"	CMC	Jola WROBLEWSKA (UL-Convenor) Joe GRYN (ULC) Bill FISKE (USNC) Mohd Nazif (SIRIM) Ilan Carmit (SII) Mr. Ray Jefferis (ASTABEAB)	To identify component standards	Re-activated following the 2006 CMC meeting



IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components CB Scheme

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
CMC-WG 5 "Components Strategic"	CMC	Paul Moliski (Convenor) (ITS U.S.A.) Klaus KRESS (VDE – DE MB) Marvin MAALOUF (ENTECLA – CA MB) Joe GRYN (ULC) Fulvio GIORGI (IMQ - IT MB) Jola WROBLEWSKA (UL – USNC MB) Bill FISKE (ITS N.A. – USNC MB) Jean LANZO (LCIE - FR MB)) Ted Gaertner (KEMA) Bill Burr (CSA International)	<ol style="list-style-type: none"> 1. Examine the current operational practices in the CB Scheme with respect to acceptance of components. <ol style="list-style-type: none"> a) Review the results of the survey carried out by the CMC-WG Component. b) Review the newly developed Guide converted into a Current Decision, Annex 1 of OD-CB2022, that has replaced Decision 1D115 on Acceptance of Components, to identify all situations in which components evaluated in an end-product by the issuing NCB may be not accepted by the recognizing NCB. 2. Carry out a strategic analysis of the current and future needs of the CB Scheme and the FCS with respect to acceptance of components. 3. Develop a proposal or proposals to substantially improve the acceptance of components, with particular emphasis on the needs and expectations related to FCS. 	To be determined
CMC-WG 6 "IECEE International Mark"	CMC	Maarten VAN DER DUSSEN (Convenor) Roy Jacobi (SAI Global) Jean-Louis ROBERT (CANADIAN-NC/IECEE) Gösta FREDRIKSSON (SEMKO) Rob FENNELL (CSA) Jonathan KOTRBA (TUV N.A.) Jola WROBLEWSKA (ULI) William H. JOHNSON (USNC/IECEE)	To explore further the idea of an International Mark monitored by the IEC.	WG disbanded following 2002 CMC Meeting, task transferred to CAB WG 7
CMC-WG 7 "Interrelation between NCBs and CBTs"	CMC	Donald A. MADER (Convenor) Joe GRYN (ULC) Wolfgang KREINBERG (TUV PS)	To update the “examples of NCBs/CBTs combinations” and provide additional clarifications.	WG Disbanded 2002-06



IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components CB Scheme

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
CMC-WG 8 "F.A.P."		Trond SOLLIE, NEMKO (Convenor) Bill Rannard (SAI Global) Joe GRYN (ULC) Nick MAALOUF (ENTECLA CA) Lu MEI (CQC) Thomas BILZ (VDE) Alberto PEDERNESCHI (IMQ) Richard PESCATORE (USNC/IECEE) Donald MADER (UL INC)	To further develop the necessary Procedure and Forms for a Factory Audit Program	WG disbanded following the creation of the FIC after the 2006 CMC Meeting
CMC-WG 9 "TRF"	CMC	Jola WROBLEWSKA (UL) (Convenor) Mauro CASARI (IMQ) Klaus KRESS (VDE)) Richard PESCATORE (USNC/IECEE) Werner HAAB (UL DE) Ralf Knapp (TUV Rh Japan)	To deal with matters pertaining to TRFs	Task completed 2001
CMC-WG 10 "Maintenance of the IECEE Rules and Operational Documents"	CMC	Pierre de RUVO (IECEE) Gosta FREDRIKSSON (IECEE Chairman) Jun XIE (IECEE Vice-Chairman) Fritz BEGLINGER (Treasurer IECEE) Don MADER (UL) Trond SOLLIE (NEMKO) Kurt HEINZ (TÜV Rh JAPAN) Kiyoto MITSUI (JISC) Gerhard DREGER (VDE) Joe GRYN (ULC) Wolfgang KREINBERG (TUV PS) Alberto PEDERNESCHI (IMQ)	To Review and update the IECEE Basic Rules, IECEE 01, the Rules of Procedure, IECEE 02, and those Operational Documents that are not under the terms of reference of existing IECEE Working Groups. To Review Current Decisions that are not within the scope of existing IECEE Working Groups and to incorporate them in the IECEE Rules, IECEE 01, the IECEE Rules of Procedure, IECEE 02 or Operational Documents as appropriate. To Refer Current Decisions that are within the scope of existing IECEE Working Groups to the appropriate WGs for incorporation into the appropriate Operational Document(s)	
CMC-WG 12 "Acceptance and Use of IEC"		Gerhard DREGER (VDE) (Convenor) Johnny Jensen (UL International DEMKO A/S)	To determine the mechanisms of seeking scope extension to new published IEC standards,	



IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components CB Scheme

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
Standards"		Bill Fiske (I.T.S NA) Joe Gryn (ULC) Osmo Väyrynen (SGS Fimko) Donald Mader (Observer) Masahiro Sato (JET) Tshepo Motsoane (SABS)	Editions, Amendments and responsibilities from NCBs when they seek scope extension of new published standards	
CMC-WG 13 "FCS Operations"		Trond SOLLIE, NEMKO (Convenor) Joe GRYN (ULC) Alberto PEDERNESCHI (IMQ) Donald MADER (UL INC)		
CMC-WG 14 "Public Information"	CMC	Kurt K. HEINZ (TUV RH JP) (CONVENOR) Bill BRYANS (BryBrook Consulting) Michel BRENON (LCIE) Alberto PEDERNESCHI (IMQ) Japan Richard PESCATORE (USNC/IECEE)	To Consider the Japanese proposal in light of the real market needs and propose a database that in addition to providing selected information related to the content of issued CB Test Certificates could also consider the issue pertaining to the National Differences	
CMC-WG 15 "Database"	CMC	Paul TAN (PSB) (CONVENOR) Wei CHEN (CQC) Yun ZHANG (CQC) Weng-Hoe CHONG (PSB) Len FLEMING (BEAB) Jola WROBLEWSKA (UL Inc.) Bill BRYANS (BryBrook Consulting)	To study the feasibility of a master searchable database that would have a global use within the IECEE operations and administration	
CMC-WG 16 "Satellite Laboratories"	CMC	Don MADER, UL Inc. (CONVENOR) Ronan MAQUESTIAU (CEBEC) Joe GRYN (ULC) Wolfgang KREINBERG (TUV PS) Michel BRENON (LCIE) Bill FISKE (ITS-USA) Johnny JENSEN (UL DEMKO)	To develop a Draft OD that integrates the various comments and concerns as well as the impact measurements.	
CMC-WG 17 "PV Manufacturers Assessment, Surveillance and Audit requirements"	CMC	L. Ji, UL Inc. (Convenor) K. Shirai (JET) W. Herrmann (TUV RH) A. Pederneschi (IMQ) Mr. Arnd Roth (VDE) Soo-Hyun PAIK (KTL) Philippe GUILLON (LCIE)	To develop the required elements for initial assessment, continuing surveillance and audit for manufacturers producing photovoltaic equipment under the IECEE CB Scheme category for photovoltaic equipment.	WG disbanded and assigned to FIC after the 2008 CMC Meeting



IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components CB Scheme

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
CMC-WG 20 “Hazardous Substances”	CMC	Jukka Vuorinen, SGS Fimko (Convenor) Ron Collis (Rockwell Automation) Ronan Maquestiau (SGS CEBEC) Dr. Ma Qiju (CQC) Alternate : Ms. Hu Nan (CQC) Michel Brenon (LCIE) Uwe Kampet (GERMAN-NC/IECEE) Karl Sander (TÜV RH DE) Toshiyuki Kajiya (JISC) Ted Gartner (KEMA Quality B.V.) Tim Duffy (Rockwell Automation)	The WG is tasked to identify the elements and procedures that can be used for product's testing and evaluation of Hazardous Substances.	2006-11-27
CMC-WG 21 “CBTC Recognition Process”	CMC	Gunsimar Paintal, UL Canada (Convenor) Michel Brenon (LCIE) Wolfgang Kreinberg (TUV PS)	<ul style="list-style-type: none"> · evaluate the elements that are currently leading to a slowing down of the Recognition process · determine and propose the corrective actions that could overcome the reason of the slow down · recommend the necessary actions to improve the “Recognition” process of CB Test Certificates by Members NCB without unnecessary 	
ad hoc CMC-WG 22 “Validity of IECEE Certificates”	CMC	Kurt Heinz, TUV RH JP (Convenor) Alberto Schiuma (IRAM) Jason Cooke (SAI Global) Bill Bryans (BryBrook Consulting) Fulvio Giorgi (IMQ) Toshiyuki Kajiya Isaac Thabo Mabena (SABS) Alternate: David Surber (TUV RH NA)	Analysis of the implications for the parties regarding the introduction of validity of CB Test Certificates and the most appropriate mechanism to establish a term of validity for CB Test Certificates.	
CMC-WG “IECEE MEE Task Force”	CMC	Alfred Dolan (convenor) Irina Antonov (SII) Michel Brossoit (CSA International) Gary Burgess (Medical Devices Assessment Section Office of Devices, Blood and Tissues Therapeutic Goods Administration) Hans Engels (IEC TC62B, WG 15) Ted Gaertner (CTL ETF 3)	To establish a consensus with methods acceptable to determine compliance with all the relevant clauses (related to ISO 14971) of IEC 60601-1 Ed. 3. To develop a Guideline document & Work Instruction on how to implement the relevant	



IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components CB Scheme

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
		<p>Convenor) Ms. Monica Gupta (SL Power Electronics (SLPE)) John Jamieson (Gary Burgess Medical Devices Assessment Section Office of Devices, Blood and Tissues Therapeutic Goods Administration) Steli Loznen (Convenor IEC/TC62/SC62A/WG17) Richard J. Markle (Philips Medical Systems) Stan Mastrangelo Steve McRoberts (UL Europe) William Midgette (FDA, USA) Joseph Murnane (UL NA) Massimo Polignano (ESAOTE S.p.A.) Geri Richter (Geri-Con) Martin Schneeberg (TUV SUD) Michael Sippl (TUV SUD / IEC SC62A) Paul Tan (TUV SUD PSB) Markus Wagner (TUV SUD) Jola Wroblewska (WG 9 Convenor) Mauro De Angiolini (IMQ)</p>	<p>clauses (related to ISO 14971) of IEC 60601-1 Ed. 3. To develop a Checklist aiming at assisting ME Industry, Official Authorities and Stakeholders around the world, Testing Laboratories and Certification Bodies to properly deal with Risk Management. To develop an addendum to the Test Report Form IEC 60601-1 to cover the overall requirements pertaining to ISO 14971. To set up the content of possible trainings to cover Risk Management issues. To be the Advisory Group on common understanding of ISO 14971 related to IEC 60601-1.</p>	
<p>CMC-WG “Software Evaluation Panel”</p>	CMC	<p>Convenor of the Technical Panel: Rafael GUIRADO – LCOE & Member of TC 61 Members of the Technical Panel: Masahiro SATO – JET & Convenor of IECEE CTL ETF 1 & Member of TC 61 Bernd GEHRKE – TC 61 & Chairman MT 23 Dieter FIETZ – TUV SUD Anura FERNANDO – UL Inc Markus Graedler - ZF Electronics GmbH Juan Carlos MOLINA MORENO – LCOE Bernhard SCHAEFERS – TUV SUD Maurizio FALORNI – IMQ Eckhard SCHWENDEMANN - ES-TMC Jola WROBLEWSKA - UL Inc</p>	<ul style="list-style-type: none"> • To establish a consensus with methods acceptable to determine compliance with Annex R of IEC 60335-1 and Annex H of IEC 60730-1 • To develop a Guideline document & Work Instruction for testing purposes on how to implement the Annex R of IEC 60335-1 and Annex H of IEC 60730-1 • To develop a Checklist aiming at assisting Household Appliances Industry, Official Authorities and Stakeholders in the global market, Testing 	



**IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components
CB Scheme**

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
		& Convenor of IECEE WG 9 Test Report Forms Ralf Schwab - VDE	Laboratories and Certification Bodies to inform the latter with the testing procedures that are going to be applied related to the requirements as specified in Annex R of IEC 60335-1 and Annex H of IEC 60730-1. <ul style="list-style-type: none"> • To develop an addendum to the TRF IEC 60335 series to cover the overall requirements pertaining to Annex R of IEC 60335-1 and Annex H of IEC 60730-1. This task will be undertaken by the IECEE WG 9 Test Report Forms however the direct input of the Technical Panel "Software Evaluation" is recommended. • To set up the content of possible trainings for NCBs/CBTLs-Manufacturers-IECEE Technical Assessors to cover Software Evaluation issues. • To be the IECEE Advisory Group on common understanding of Annex R of IEC 60335-1 and Annex H of IEC 60730-1 	
CMC-WG 23" Counterfeit"	CMC	Jean-Pierre ISNARD (convenor) Richard Pescatore Don Mader (UL Inc.) Toshiyuki Kajiva (Panasonic) Yu Zida (Haier) Mike Lawson (Intertek) Vladimir Filiac (EZU) Luca Taglioretti (IMQ) Katharina Seidel (TUV RH DE)	To be determined	



IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components CB Scheme

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
CMC-WG 24 "Infringement"	CMC	Don Mader (Convenor) Trond Sollie (NEMKO) Wolfgang Kreinberg (TUV SUD) Ms. Bo Yumin (CNCA) Richard Pescatore (USNC IECEE) Joe Gryn (UL Canada) Ms P Mazibuko (NRCS) M. Brénon (LCIE)	To be determined	

[Back to index](#)



**IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components
CB Scheme**

FCS – TASK FORCES and WORKING GROUPS

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
FCS TASK FORCE "A"	CMC	Past IECEE Secretary	To develop <ul style="list-style-type: none"> ◆ Questionnaire to determine what NCBS are interested in participating in the CB-FCS 	ON HOLD
FCS TASK FORCE "B"	CMC	Pierre de RUVO (Convenor)	To develop <ul style="list-style-type: none"> ◆ Mfr Conformity Assessment Procedures ◆ Mfr Q.S. Questionnaire ◆ Audit Report Form 	ON HOLD
FCS TASK FORCE "C"	CMC	Don MADER (Convenor)	To develop <ul style="list-style-type: none"> ◆ CAC ◆ FCS Agreement ◆ Rider to Agreement 	ON HOLD
FCS TASK FORCE "D"	CMC	Trond SOLLIE (Convenor)	To develop <ul style="list-style-type: none"> ◆ Application Form ◆ Audit Check List 65 ◆ Audit Check List 25 ◆ Template Ass. Rep. ◆ Certificate for accepted NCBS 	ON HOLD
WG 2 REVISION IECEE 03	EVA-G	P. de RUVO (Convenor) P. LEONG (PSB) A.PEDERNESCHI (IMQ) J. SJÖBERG (SEMKO) T. SOLLIE (NEMKO) J. WROBLEWSKA (UL)	To revise the Rules of Procedure of the CB-FCS	Pending the issue from the WG "FCS Operations"
WG 1 Peer Assessment Guidelines	EVA-G	A. PEDERNESCHI (Convenor) A.PEDERNESCHI (IMQ) T. SOLLIE (NEMKO) B.WINTHER (DEMKO)	To produce Guidelines pertaining to Peer Assessment activities	Permanent review

[Back to index](#)



**IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components
CB Scheme**

CTL WORKING GROUPS and TASK FORCES

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
CTL-WG 1 Accuracy/ Uncertainty		R. VAICKAUSKI (UL – Convenor) D. BARBINI (CSA Int.) M.LESCURE (LCIE) M. HINGOTT (TUV PS) J.OLOGBOSERE (TUV RH JP) M. ANDERSEN (NEMKO) S. SARACINO (IMQ) B. JANSSON (SEMKO) B.BREITENBACH (VDE) J.O. STILLING (INTERTEK) S. NONAKA (JAB) Z. Wang (CQC)	To develop an IECCE position paper detailing the rationale why accuracy is the preferred approach for the IECEE Laboratories. To develop a procedure/guide to be used by all CBTLs so as to show accreditors and peer assessors that the IECCE is following a consistent approach when the expression of Uncertainty Measurement is absolutely necessary, with regard to clause 5.4.6 of ISO/IEC 17025.	Revised draft for CTL agenda by March 2002
CTL-WG 2 PTP	CTL	H. Bachi (CTI, Convenor) M. Sato (Convenor ETF 1) R. Wunderer (Convenor ETF 2) T. Gaertner (Convenor ETF 3) A. Bretz (Convenor ETF 4) E. Parma (Convenor ETF 5) JP. Barbier (Convenor ETF 10) R. Vaickausti (Convenor WG1 & WG3) Mr. L. Ji (Convenor ETF 9) K. Wilson (Wakefield Labs) D. BARBINI (CSA Int.) X. Mo (CQC) Z. Egozi (SII) J. Pierce (ITS USA) I. Flemming (IFM) W. Strzelecki (Convenor ETF 11) Ms. Zhu (Convenor ETF 6) U. Krischke (Convenor ETF 12)		On Going
CTL-WG 3 Editing Group	CTL	Ronald VAICKAUSKI (UL- Convenor) Hubert BACHL (CTI) Marc LESCURE (LCIE) William FISKE (ITS-USA) C.SWEE-GEE (PSB) Arkadiusz SALWA (UL Inc.)	To review the CTL Decisions sheets and to coordinate with the ETFs on the wording to be used.	On Going
CTL-WG 4		E. Parma (Convenor)		On Going



IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components CB Scheme

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
Coordination		<p>M. Sato (Convenor ETF1) R. Wunderer (Convenor ETF2) T. Gaertner (Convenor ETF3) A. Bretz (Convenor ETF 4) Ms. Zhu (Convenor ETF6) R. Vaickauski (Convenor WG1 & WG3) Mr. L. Ji (Convenor ETF 9) H. Bachl (Convenor WG2 and Convenor ETF 7 ad interim) J.P. Barbier (Convenor ETF10) W. Strzelecki (Convenor ETF11) U. Krischke (Convenor ETF 12)</p> <p>Mr. Bengt Jansson (Convenor CTL ETF 13)</p>		
TASK FORCE 1	CTL	<p>M. Sato (Convenor) G. Camiciotti (IMQ) Technical Advisor G. Bukkjaer (UL International Demko A/S) Technical Advisor TOYS</p> <p>J.D. Gonzales (IRAM) K. Wilson (Wakefield Labs) T. Lornitzo (TGM-VAE) F. Rosenberger (OVE) G. Tarseos (CSA) H. Wang (CQC) Z. Jurda (EZU) G. Bukkjaer (UL International Demko A/S) O. Väyrynen (FIMKO) A. Barrere (LCIE) B. Poesl (LGA Nürnberg) M. Hingott (TÜV PS) D. Fietz (TÜV PS) P. Krakau(TÜV Rheinland) R. Gottschling (VDE) Z. Zsákai (MEEI) J. Sumiya (JET) A. Sasaki (JQA) Jong-Koo Park(KTL) Mr. van Aalderen (KEMA) T. Ulsrud (NEMKO) E. Cardoso (IEP) E.G. Chia (PSB)</p>	Household and similar equipment (HOUS) Portable tools (TOOL) and TOYS	On Going



IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components CB Scheme

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
		M. Zontar (SIQ) R. Guirado (LCOE) L. Mattson (SEMKO) R. Slupinski (UL) J. Stimitz (UL) L. Yap (Intertek Shanghai) K. Park (KTL) A. Renn (TUV Rheinland HK)		
TASK FORCE 2	CTL	R. Wunderer (Convenor) M. Andersen (NEMKO) Technical Advisor IEC 60065 & IEC 60950 T. Burke (UL) Technical Advisor IEC 60950 T. Shiota (JQA) Technical Advisor IEC 60065 & IEC 60950 K. Wilson (UL International New Zealand) J.D. Gonzales (IRAM) T. Thun (TGM-VAE) X. Xiao (CQC) F. Homolka (EZU) J. J. Jensen (UL International Demko A/S) T. Silonsaari (FIMKO) J. Lanzo (LCIE) M. Hingott (TUV PS) H. Frerk (VDE) A. Arndt (TÜV Rheinland) K.-H. Gompf (VDE) I. Seres (MEEI) F. Brivio (IMQ) B. Burek (Intertek) T. Kuboki (JET) J. Ologbosere (TUV Rheinland Japan) Jin-Soo Kim (KTL) A. Bergervoet (KEMA) M. Ng (PSB) M. Kiselja (SIQ) B. Jansson (SEMKO) P. Cross (NEMKO) D. Bras (EMITECH) V.K. Truong (Electrosuisse) C. Sato (UL Inc.) Y-S Lee (KETI) B Lowe (CSA International) E. Yap (CSA International)	Electronics and entertainment (TRON) IT and office equipment (OFF)	On Going
TASK FORCE 3	CTL	T. Gaertner (Convenor) H. Sattler (VDE) Technical Advisor R. A. Wunderer (OPFZ)	Electrical equipment for medical use (MED) Measuring equipment (MEAS)	On Going



**IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components
CB Scheme**

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
		A. Parzer (TÜV-A) F. Homolka (EZU) J. Lanzo (LCIE) O. A. Nielsen (UL International Demko A/S) M. Mentula (SGS FIMKO) M. Sippl (TUV PS, Convenor SC 62A/WG 14 - Liaison Officer) D. Fietz (TUV PS) L. Freudenreich (TÜV Rheinland) V. Ebinghaus (TÜV Rheinland) R. Schoensteiner (LGA) I. (Seres MEEI) M. De Angiolini (IMQ) F. Skarpsno (NEMKO) M. Kiselja (SIQ) P. Lymeus (SEMKO) V.K. Truong (Electrosuisse) G. Hines (ITS T&C) J. Murnane (UL) S. Poutissou (CSA) M. Brossoit (CSA) B. Burek (Intertek) Andreas Nilsson (Nemko A.S.)		



IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components CB Scheme

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
TASK FORCE 4	CTL	Andreas Bretz (VDE) (Convenor) H. Bachl (CTI) Technical Advisor B. Hedlund (SEMKO) Technical Advisor B. B. Doyeo (IRAM) G. Miscovich (IRAM) C. Prochaska (TGM-VAE) S. Piras (SGS CEBEC) W. Zhang (CQC) M. Sobeslavsky (EZU) Lars T. Hansen (UL International Demko A/S) S. Lokfors (FIMKO) P. Balaire (ASTABEAB) P. Nagy (MEEI) F. Brivio (IMQ) M. Casari (IMQ) K. Hasegawa (JET) Sung-Hee Mo (KTL) H. Barends (KEMA) R. Hendriksen (KEMA) J. Costa (ISQ) J. Santos (CERTIF) E. Venek (SIQ) T. de Frutos (AENOR) M. Huber (Electrosuisse) C.S. Kurten (UL) J.S. Antony (UL) Y. Liu (CQC) I. Szecsei (MEEI)	Installation accessories and connecting devices (INST) Switches for appliances and automatic controls for electrical household appliances (CONT) Capacitors as components (CAP) BATT MISC	On Going
TASK FORCE 5	CTL	E. Parma (Convenor) P. Kaufmann (VDE) Technical Advisor A.D. Hughes (Thorn Lighting Ltd. - Expert from Industry) Technical Advisor B. B. Doyeo (IRAM) G. Miscovich (IRAM) C. Prochaska (TGM-VAEE) R. Stoegmuller (OVE) S. Chen (CQC) F. Jandura (EZU) G. Bukkjaer (UL International Demko A/S) W. Parmiani (UL International Italia) P. U. K. Orrevetelainen (SGS FIMKO) M. Lescure (LCIE) D. Fietz (TUV SUD PS) H. Kilb (VDE) W. Menger (VDE) M. Kato (JET)	Lighting (LITE) Safety transformers and similar equipment (SAFE)	On Going



**IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components
CB Scheme**

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
		S. J. UK (KTL) H. Telindert (KEMA) T. Drost (KEMA) J. Lopes (LIQ) E. Venek (SIQ) A. Valladolid (LCOE) R. Webster (Intertek Testing and Certification) Mr. S. Poole (L.A.L.) Ms. A. Branco (CERTIF) H.-K. Tan (TUV SUD PSB) F. Tironi (FLOS - Expert from Industry) T. Andersson (SEMKO) M. Stalder (Electrosuisse) C. Maes (SGS CEBEC) S. Shen (LCIE China) R. Mantegazza (MQ) P. Painini (IMQ) P. Jong Koo (KTL) F. Esdohr (TRLP) P. Bacurik (EVPU) G. Klinger (TÜV Rheinland) E. Yap (CSA International)		
TASK FORCE 6	CTL	Zhu (TICW –Convenor) I. McGuinness (BSI) Technical Advisor J. Tuma (EZU) S. Lokfors (FIMKO) C. Mazzucchi (IMQ) O.A. Nielsen (UL International Demko A/S) G. Mackenbach (KEMA) F. Shirai (JET) Hoowo Kang (KTL) A.C. Figueiral (CERTIF) J.M. Cruz (ISQ) H. Chuan Wee (PSB) T. Kokelj (SIQ) N. Tjapkin (GAMA)	Cables and cords (CABL)	On Going
TASK FORCE 7	CTL	Mr. Bachl (CTI) - Convenor ad interim S. Piras (SGS CEBEC) M. Sobeslavsky (EZU) V. Fiederichs (International Product Safety GmbH) J.-F. Bruel (LCIE) S. Lautamies (FIMKO) A. Bretz (VDE) P. Nagy (MEEI) M. Casari (IMQ) S.P. Ahn (KERI)	Low voltage high power switching equipment installation (POW) Protective equipment (PROT)	On Going



**IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components
CB Scheme**

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
		H. Kormelink (KEMA) A. Orte (AENOR) B. Hedlund (SEMKO) F. Rusnati (Assil)		
TASK FORCE 8	CTL	D.W. O'Shea (onvenir) L.T. Hansen (UL International Demko A/S) N. Nakamura (JET) T. Yamada (JQA) N. Tjapkin (GAMMA)	Plastics	Disbanded during the CTL meeting in Johannesburg 2006-04-18
TASK FORCE 9	CTL	L. Ji (UL Inc.) -Convenor W. Herrmann (TUV RH) A. Roth (VDE) J. H. Wohlgemuth (BP SOLAREX) N. Wilmot (Murdoch University) Y. Murakami (JET) H. Barikmo (TC82) T. Zgonena (UL inc.) Dr. P. Varadi (PV Gap) W. Kang (CQC) S. Wu (Intertek Taiwan) C. Hee (Intertek Singapore) C. Roversi (IMQ S.p.A.) S. Poutissou (CSA International) G. Bellenda (Eurofins) G. Bogdan (MEEI Kft)	Photovoltaics	On Going



IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components CB Scheme

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
TASK FORCE 10	CTL	JP. Barbier (LCIE - Convenor) B. Berglof (Intertek Semko) D. Rivoltella (Sicur Control, UL International Demko A/S) J. Zheng (CQC) K.W. Friedrich (TUV Rheinland) J. Nyman (Nemko) S. Kloska (VDE) A. Van Der Meijden (KEMA) H. Yamashita (JET) S.-J. Kim (KTL) J. Merikari (SGS Fimko) T. Hada (JQA) C. Cantaluppi (IMQ) G. Gamperi (TGM-VAEE) R. Guirado (LCOE) B. Delisi (UL Inc) C. Hauser (Electrosuisse) M. Mak (SIQ) J. Deng (TUV SUD PSB) J. Merikari (SGS FIMKO) Y. Litvinov (Intertek)	Electromagnetic Compatibility	On Going
TASK FORCE 11	CTL	Mr. W, Strzelecki (TUV RH N.A.) Convenor N. Stoev (CSA International) Technical Advisor R. Wunderer (OVE) K. Tachihara (JQA) B. Venturelli (IMQ) Chul-Joo Jeon (KTL) A. Bergervoet (KEMA) M. Kiselja (SIQ) B. Jansson (SEMKO) V.K. Truong (Electrosuisse) I. Antonov (SII) P. Boden (UL) V. Ebinghaus (TUV RH DE) A. Roth (VDE) V. Kalakutskiy (TUV RH JP) T. Wong (CSA International) O. Stilling (Intertek Semko Shanghai) Y. E. Teong (TUV SUD PSB) K.J. Puckett (TUV SUD PS) M. H. Han (KETI)	Lasers	



**IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components
CB Scheme**

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
TASK FORCE 12	CTL	Dr. U. Krischke (SGS-Germany) Convenor J. Han (SGS- Korea) A. Majjala (SGS- Finland) C. Chu (SGS- Taiwan) G. Fong (SGS- Taiwan) K. Goto (SGS- Japan) S. MacLeod (UL-US) M. Jahns (TUV SUD) H. Hinrichs (Bureau Veritas Consumers Product Services GmbH) M. Cheng (Nemko Shanghai) C. List (Intertek Consumer Goods GmbH) T. Norlem (Intertek Semko AB) D. Elks (Intertek) N. Sözer Güllü(Intertek Testing Services Turkey)	Hazardous Substances	
TASK FORCE 13	CTL	Bengt Jansson (Intertek Semko AB) - Convenor Laurie Florence (UL Inc.) Hyun-Jong Jun (KTL) Saadia Jebnoun (LCIE Bureau Veritas) Jean Lanzo (LCIE Bureau Veritas) Kun-Jeng Liang (UL Taiwan Co., Ltd.) Sammy Wu Wu (Intertek Taiwan) Raymond Zhou (Intertek China) Jody Leber (SGS) Timo Silonsaari (SGS Fimko) I. Szecsei (MEEI)		

[Back to index](#)



**IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components
CB Scheme**

IEC CAB TECHNICAL PANEL

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
IEC-CAB TECHNICAL PANEL		Mr. P. de Ruvo (Convenor) Mr. D. Mader (UL Inc.) Mr. J. Gryn (ULC) Mr. C. Agius (IECEX) Mr. U. Klausmeyer (Observer) Mr. N. Mueller (?) Mr. J. Hattingh (?) Mr. J. Mitchell (?) Mr. C. Watson (?) Ms. M. Malmqvist (SWEDAC)		

[Back to index](#)



**IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components
CB Scheme**

JWG – JOINT WORKING GROUP

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
JWG “COMMON UNDERSTANDING OF ISO/IEC 17025”		Mr. de Ruvo (Convenor) Mr. A. Pederneschi (IMQ) Mr. D. Mader (UL Inc.) Mr. J. Gryn (ULC) Mr. J. Xie (CNCA) Mr. W. Kreinberg (TUV PS) Mr. M. Wittner (IRAM) Mr. T. Sollie (NEMKO) Mr. G. Dreger (VDE) Mr. C. Agius (IECEX) Mr. U. Klausmeyer (IECEX) Mr. N. Mueller (?) Mr. J. Hattingh (?) Mr. S. Sydney (?) Mr. J. Mitchell (?) Mr. C. Bestwick (UKAS) Mr. C. Watson (?) Mr. L. Bauder (METAS) Ms. M. Malmqvist (SWEDAC)		

[Back to index](#)